

Notice of References Cited

Application/Control No.

10/811,007

Applicant(s)/Patent Under
Reexamination
CHEN ET AL.

Examiner

JONATHAN G. STERRETT

Art Unit

3623

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	U	"SAP Partnership", 2001 webpage of PMGBenchmarking.com, retrieved from http://web.archive.org/web/20010210225119/www.pmgbenchmarking.com/sap/sap_4.html
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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